

Topic Title: 02. Special Session II: AI for Display

Session Title: 06. Poster Session 2

[06_02_1163]

Deep Learning Based Inverse Design Model for Blue OLED Materials

Eunkyung Koh, Seran Kim, Dahye Cho, Sohae Kim, Iljoon Kang, Sunmi Choi, Saena Yoon, Hoilim Kim, Young Mi Cho, Seungjin Baek, and Yongjo Kim (Samsung Display Co., Ltd., Korea)

[06_02_1267]

Image Enhancement Using Frequency Transform for Deep Learning Based Defect Detection

Mi-Sun Kang, Junghwan Kim, and Anthony S Son (Samsung Display Co., Ltd., Korea)

[06_02_1275]

Improved Optimization of Computer-Generated Holograms through Average Shift

Dongheon Yoo and Byoungcho Lee (Seoul Nat'l Univ., Korea)

[06_02_1282]

A Study on Simulation and Machine Learning about Full Channel Model for High-Frequency Displays

Hyochul Lee, Jiwon Kim, Hyeondo Park, Insoo Wang, Yudeok Seo, Dongjin Seo, and Yongjo Kim (Samsung Display Co., Ltd., Korea)

[06_02_1305]

Deep Knowledge Transfer for Classification of Imbalanced Defect Image Datasets of Display Panels

Minui Hong, Jinseo Jeong, Jinsu Yoo (Seoul Nat'l Univ., Korea), Sunghoon Jo, Jaewon Kim (Samsung Display Co., Ltd., Korea), and Gunhee Kim (Seoul Nat'l Univ., Korea)

[06_02_1308]

Web based Display Simulation and Visualization Platform

Junghoon Jo, Jiyoung Park, Jihoon Shin, Eunji Kim, and Yongjo kim (Samsung Display Co., Ltd., Korea)

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[06_02_1312]

A More Reliable Defect Detection and Performance Improvement Method for Panel Inspection based on Artificial Intelligence

Eui-Young Jeong, Jong-Myong Choi, Won-Hyouk Jang, and Hee-Yeon Kim (Samsung Display Co., Ltd., Korea)

[06_02_1314]

Time Series Display Property Forecasting with Long Short-Term Memory

Younggil Jin, ChangHun Lee, and Won-Hyouk Jang (Samsung Display Co., Ltd., Korea)

[06_02_1315]

Detecting and Measuring Unstructured Particles on Panel Surface Using Semantic Segmentation

Jiyoun Shin, Taeseok Jeong, Seokkwon Kim, and Yongjo Kim (Samsung Display Co., Ltd., Korea)

[06_02_1326]

Driving Optimization for Defect Detection

Yongbin Kim, Hyunyoung Choi, Gunwoo Yang, and Yongjo Kim (Samsung Display Co., Ltd., Korea)

[06_02_1332]

Improvement of Prediction Accuracy in Large PR Patterns Using Bake Model

Sunil Choi, Jong-Heon Park, Sung-Hwan Hong, Sung-Jun Kim, Hyung-Keon Cho, Seok-Beom You, Gun-Shik Kim, and Yong-Jo Kim (Samsung Display Co., Ltd., Korea)

[06_02_1343]

Acceleration of RC Extracting Simulation for Data Mining in Panel Circuit Design and Optimization

Il Hwa Jeong, Wan Seok Kang, Moosung Jung, and Sukin Yoon (Sanayi System Co., Korea)

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[06_02_1345]

AI based TSP Sensitivity Real-Time Prediction Model

Keuk Jin Jeong, Young Gu Kang, Hyun Sung Park, Yudeok Seo, Dongjing Seo, and Yongjo Kim (Samsung Display Co., Ltd., Korea)

[06_02_1368]

Phase-Only Hologram Encoding Method via Iterative Fourier Transform Algorithm

Jaebum Cho, Jewon Yoo, Daewook Kim, Sang-Gu Lee, Hyunguk Cho, Seungjin Baek, and Yongjo Kim (Samsung Display Co., Ltd., Korea)

[06_02_1399]

Detection of Defect Cause Analysis with Production Pathway

Kyu Seok Kim (KAIST, Korea), Eugene Kim, Dae Youn Cho (Samsung Display Co., Ltd., Korea), and Il-Chul Moon (KAIST, Korea)

[06_02_1410]

Deep Learning-Based Mura Detection With Atrous Spatial Pyramid Pooling

Jou Won Song, Namhyun Ahn, and Suk-Ju Kang (Sogang Univ., Korea)

[06_02_1438]

Development of a PSA Delamination Index on Flexible Displays for AI Prediction

Jisoo Kim, Kyoungah Lee, Hyoyul Yoon, Mingu Kim, Eunhye Kang, Taekyoung Hwang, and Dongjin Seo (Samsung Display Co., Ltd., Korea)

[06_02_1464]

Improvement of Display Panel Defect Detection based on Tree-Based Machine Learning Method

Jaewoong Kim, Wooyoung Jeong, Taejin Hwang, Kyungeun Park, and Jinpyo Jun (Samsung Display Co., Ltd., Korea)

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[06_02_1490]

A Physics-Driven Frequency Domain Neural Network Model for Lithographic Analysis

Heehwan Lee, Minjong Hong, Min Kang, Hyun Sung Park, Kyusu Ahn, Youngwoo Lee, and Yongjo Kim (Samsung Display Co., Ltd., Korea)

[06_02_1556]

Simplified Full-Azimuth WAD Simulation for Sloped OLED Panel

Yong Sub Shim, Younho Han, Jong Beom Hong, Young Jun Yoo, and Reehyang Kim (Samsung Display Co., Ltd., Korea)

[06_02_2000]

Deep Depth Extraction of Multi-View Images for Holographic 3D Content

MinSung Yoon, Hyeonji Kim, and HwaSeon Yeo (ETRI, Korea)